1	Type BRS	1.# L1	Hits 4081	Search Text wafer and batch\$3 near1 process\$3	T; 16;58 US-P	Won E 0
2	BRS	L2	5	l and workpiece and tool and state and metrology and rout\$3 and correlation	GPUB USPA:2004/10/15 T; 19:44 US-P GPUB	0
3	IS&R	L3	1	("6773931") PN	USPA:2004/10/15 T; 19:44 US-P GPUB	0
ı	BRS	L4	1	3 and fault	USPA 2004/10/15 T; 19:45 US-P GPUB	0
5	BRS	L5	1	3 and (fault or error)	USPA 2004/10/15 T; 19:45 US-P GPUB	0
5	BRS	L6	1	5 and detect\$3	USPA:2004/10/15 T; 19:51 US-P GPUB	0
7	BRS	L7	0	3 and position	USPA:2004/10/15 T; 19:51 US-P GPUB	0
8	BRS	L8	0	3 and modify\$3	USPA:2004/10/15 T; 19:52 US-P GPUB	0
9	BRS	L9	0	3 and queue	USPA:2004/10/15 T; 19:52 US-P GPUB	0
10	BRS	L10	0	3 and sampl\$3	USPA:2004/10/15 T; 19:53 US-P GPUB	0
11	BRS	LII	0	3 and trigger	USPA 2004/10/15 T; 19:53 US-P GPUB	0
12	BRS	L12	1	3 and ingger\$3	USPA:2004/10/15 T; 19:53 US-P GPUB	0
13	BRS	L13	1	"6587744" PN.	USPA 2004/10/15 T 19:56	0
				"6444481" PN	USPA:2004/10/15 T 19:56	0
15	BRS	L15	i	"6408220".PN.	USPA:2004/10/15 T 19:57	0
16	BRS	L16	1	"5270222" PN.	USPA:2004/10/15 T 19:57	0
17	BRS	L17	ī	"6587744".PN	USPA 2004/10/15 T 19:58	0

East search Notes

	e e e	Document ID US 20040059456 A1	20040325			700/121	Current XR Retrieval (Inventor Bode, Christopher A. et	S C
	r r r	US 20040029299 A1	20040212	20	Dynamic targeting for a process control system	438/5	700/121	Pasadyn, Alexander J. et al.	₩. F
	rnn	US 20010039462 A1	20011108	28	System and method for predicting software models using malerial-centric process instrumentation	700/45		Mendez, Rafael et al.	e r
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₽	enn	US 6650955 B1	20031118		Method and apparatus for determining a sampling plan based on process and equipment fingerprinting	700/108	438/14; 438/16; 438/17; 438/18; 700/109: 700/110; 702/83	Sonderman, Thomas J. et al.	r r